

	SIM CA	RD CONNECTOR Frame	e WITH PIVOT ARM	
1.0	SCOPE			$\sim$
	This Product Specification c requirements and test method			tal performances
2.0	PRODUCT DESCRIPTION			
	2.1 PRODUCT NAME AND	SERIES NUMBER(S)		))
	Product Name		S	eries Number
	BLOCK SIM CONNECTOR		Δ.	151130
	2.2 DIMENSIONS, MATER	IALS, PLATINGS AND I	MARKINGS	
3.0	See Sales Drawing (R)SD-1 markings. APPLICABLE DOCUMENT			erials, platings and
	The following documents for event of conflict between the product drawing shall take p	e requirements of this spe		
4.0	RATINGS			
	4.1 CURRENT RATING 0.5Amps Max. per conta	act		
	4.2 VOLTAGE RATING 10 Volt DC Max.			
	4.3 TEMPERATURE Operating:	- 40°C to + 85°C		
THIS S TEST D	ATIVE RELEASE: PECIFICATION IS BASED ON DATA MAY EXIST, BUT THIS S DITIONAL TESTING AND EVAL	PECIFICATION IS SUBJEC		
REVIS	ION: ECR/ECN INFORMATION:		38MM HEIGHT	SHEET No.
	<u>EC No:</u> S2015-1507 <u>DATE:</u> 2015/06/24	-	SIM CONNECTO	<b>R</b> 1 of 7
/	MENT NUMBER:	CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:
4_	PS-151130-0001	Wang HL 2015/06/25	Jenny Zeng 2015/06/25	Victor Lim 2015/06/25
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#### 5.0 MECHANICAL INTERFACE

#### 5.1 CARD INTERFACE

SIM card interface: GSM 11.11 specification

#### **5.2 PWB INTERFACE**

Plating on PWB pads: OSP plated

#### 6.0 PERFORMANCE

#### 6.1 ELECTRICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
1	Low Level Contact Resistance (LLCR)	Mate connectors with dry circuit (20 mV, 100mA MAX) on mated connector. Refer to appendix 1. (EIA-364-23C)	<b>50</b> milliohm max [initial] Value includes bulk resistance of terminal or Detect switch
2	Insulation Resistance	Apply a voltage of 100 V DC between adjacent terminals. Electrification Time: 1 min (EIA-364-21D)	1000 Megohms minimum
3	Dielectric Withstanding Voltage	Unmated connectors: apply a voltage of <b>500</b> VAC between adjacent contact for <b>1</b> minutes (EIA-364-20C)	No voltage breakdown
4	Temperature Rise	Mated and measure the temperature rise of contact, when rated current is passed. (EI/-364-70B) Method1	Temperature Rise <b>30°C</b> max

## 6.2 MECHANICAL REQUIREMENTS

ITEM			REQUIREMENT
5	Durability (Horizontal Insertion Direction)	compress terminal vertically to 1500 cycles at a maximum rate of 720cycles/hour.	Contact resistance ∆ <b>30</b> milliohms max

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	DOCUMENT NUMBER:	CREATED / REVISED BY:	CHECKED BY:	APPRO	<u>OVED BY:</u>
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mc	olex	<u>®</u>	PRODUCT SPECIFIC	ATION
	6	Contact Normal Force	Measure contact normal force at <b>0.20mm</b> away from housing top surface and at <b>maximum deflection</b> (0mm from housing)	0.20N min 1.35N max
	7	Vibration	Sine Vibration, 10g peak Frequency: 10~500Hz, 2 cycles per axis 15 mins per cycle (EIA 364-28F) – Test Condition II	Contact resistance Δ <b>30</b> millionms max Discontinuity < 1 μs
	8	Mechanical Shock (specified pulse)	Pulse shape = half sine Peak acceleration = 490m/s2 (50G) Duration of pulse = 11ms Apply 3 successive shocks in each direction along the 3 mutually perpendicular axes. (EIA 364-27B) – Test condition A	Contact resistance Δ <b>30</b> milliohms max Discontinuity < 1 μs
	9	Solder Joint Peeling Strength	Apply a load to the Nano SMI connector parallel to the PWB (Cdirection)	<b>15N</b> minimum

### 6.3 ENVIRONMENTAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
10	High Temperature Storage Life (steady state)	At +85°C for 120 hours Recovery: 1~2 hours at ambient atmosphere	Contact resistance $\Delta 30$ milliohms max
11	Thermal-Shock	Expose the mated connectors to the following condition for 5 cycles (60 mins/cycle): -55 °C (30 min) ← 105 °C (30 min) Transit time shall be within 5 mins (Max) (EIA-364-32E) - Test condition VI	No mechanical damage, corrosion and oxidation at contact area Contact resistance Δ <b>30</b> milliohms max

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	DOCUMENT NUMBER:	CREATED / REVISED BY:	CHECKED BY:	APPRO	OVED BY:
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otex	@	PRODUCT SPECIFICA	ATION
12	Cyclic Humidity	Cycle the part between 25°C+/-3°C at 80%+/-3%RH and 65°C+/-3°C at 50%+/- 3%RH Ramp times should be 30mins and dwell times to be 1hour. Dwell times start when temp and humidity have stabilized within the specified levels. Perform 24 cycles	Contact resistance ∆ <b>30</b> milliohms max Insulation resistance <b>1000</b> Megohms max No voltage breakdown
13	Solderability	Solder paste is deposited on a ceramic plate via stencil. The connectors are steam aged and placed onto the solder paste print. The substrate is processed through a forced hot convection oven. Refer to section 9.0 for temp profile. The connectors are removed from the ceramic and inspected. Steam Aging: 1 hour (ANSI-J-STD 002)	Solder coverage = 95% minimum
14	Resistance to Soldering Condition	Unmated sample to be passed through reflow over according to temp profiles (shown in section 9.0) See Graph below	No mechanical damage

### 7.0 PACKAGING

Parts shall be packaged to protect against carnage during handling, transit and storage. The parts shall be carried in reels inside boxes. For details, kindly refer to Packaging spec (R)PK-151130-0001 and Sale drawing (R)SD-151130-0001.

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	REVISION: ÉGR/ECN INFORMATION:	TITLE:			SHEET No.
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### 8.0 TEST SEQUENCES

	Group	Group	Group	Group	Group	Group	Group
Test Group →	1	2	3	4	5	6	
Test or Examination ↓						$  \rangle$	$\searrow$
Sample size	5	5	5	5	5	5	X X
1. Low Level Contact Resistance (LLCR)	3,5,8,10	2,5				-	-/
2. Insulation resistance			2,6			$\nabla$	
3. Dielectric withstanding voltage			3,7			))	
4. Temperature Rise				2			
5. Durability	4						
6. Contact Normal Force	2,6			//			
7. Vibration		3		$\langle  \rangle$	$\overline{\gamma}$		
8. Mechanical Shock		4			/		
9. Solder Joint Peeling Strength				$\int$	2		
10. High Temperature Storage Life (steady state)			$\sim$	P		3	
11. Thermal Shock	7		$\overline{4}$	1			
12. Cyclic Humidity	9	$\square$					
13. Solderability		$\langle \langle \rangle \rangle$					1
14. Resistance to Soldering Condition			1	1	1	1	
14. Resistance to Soldering			1	1	1	1	
14. Resistance to Soldering Condition	1 TITLE:					1	SHEE
14. Resistance to Soldering Condition	TITLE:	BLO	0.38M CK SIN	M HEIC	GHT NECTC	DR	<b>5</b> of
14. Resistance to Soldering Condition	TITLE:	BLO	0.38M CK SIN	MHEIC	SHT NECTC	D <b>R</b>	



